

FORM PTO-1449		US Dept. of Commerce Patent and Trademark Office		ATTORNEY DOCKET NO. 2771-161 CON		SERIAL NO. Not Yet Assigned		
INFORMATION DISCLOSURE STATEMENT  (use several sheets if necessary)				APPLICANT Tischler, et al.				
				FILING DATE August 14, 2001		GROUP		
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.								
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER INITIAL		PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
MJ	AA	4,727,047	2/23/88	Bozler et al.	437	089		
/	AB	4,931,132	6/5/90	Aspnes et al.				
	AC	4,622,083	11/11/86	Shih				
	AD	5,334,277	8/94	Nakamura	117	102		
	AE	3,598,526	8/10/71	Humi et al.	23	192		
	AF	3,634,149	1/11/72	Knippenberg	148	175		
	AG	3,326,820	6/20/67	Cuomo et al.	252	478		
	AH	5,954,874	9/21/99	Hunter	117	84		
	AI	5,919,305	4/6/99	Solomon	117	90		
	AJ	5,846,844	12/8/98	Akasaki et al.	437	21		
	AK	5,385,862	1/31/95	Moustakas	437	107		
	AL	3,829,556	8/13/74	Logan et al.	423	409		
	AM	5,146,465	9/8/92	Khan et al.	372	45		
	MJ	AN	5,433,169	7/18/95	Nakamura	117	102	
	<b>FOREIGN PATENT DOCUMENTS</b>							
			DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
MJ	AO	JP56-59700A	10/17/79	JAPAN				
MJ	AP	62183399	6/22/87	JAPAN				
<b>OTHER DOCUMENTS (Including Author, Title, Journal-Date, Page Number, Etc.)</b>								
MJ	AQ	Derwent Abstract of JP 56-59700A; Matsushita Elec Ind Co.; "Gallium Nitride Thin Single Crystal Film"; 1979						
/	AR	"Defect reduction in GaAs epitaxial layers using a GaAsP-InGaAs strained-layer superlattice," Tischler et al., Appl. Phys. Lett. 46(3), pp. 294-296 (1985)						
	AS	"GaN, AlN, and InN: A review," Strieter, S., and Morkoc, J. Vac. Sci. Technol. B 10 (4), 1237-1266 (1992)						
MJ	AT	"Current Status of GaN and Related Compounds as Wide-Gap Semiconductors," Matsuoka, T., J. Crystal Growth 124, 433-438 (1992)						
Continue on Page ____								
EXAMINER <i>Math J</i>					DATE CONSIDERED 6/30/2005			

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<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
M>	AU	5,239,188	8/24/93	Takeuchi et al.	257	76
	AV	5,006,914	4/9/91	Beetz, Jr.	357	61
	AW	5,373,171	12/13/94	Imai et al.	257	77
	AX	3,922,703	11/25/75	Pankove	357	17
M>	AY	4,985,742	12/15/91	Pankove	357	34
<b>FOREIGN PATENT DOCUMENTS</b>						
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